

Search Notes

Application/Control No.

10/587,167

Examiner

Patricia T. Nguyen

Applicant(s)/Patent under
Reexamination

TANAKA ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	129	8/10/2007	PN
	124R		
	310		
	207A		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
330	129	8/10/2007	PN
	124R		
	310		
330/207A			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST		